

<b>Notice of References Cited</b>	Application/Control No. 10/567,684	Applicant(s)/Patent Under Reexamination TAKAYASU ET AL.	
	Examiner Forrest M. Phillips	Art Unit 2837	Page 1 of 4

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-3,476,636 A	11-1969	CROSBY DAVID W	428/92
*	B	US-4,194,037 A	03-1980	Stoller, Frederick L.	428/92
*	C	US-4,432,433 A	02-1984	Ogawa, Naoki	181/204
*	D	US-4,490,425 A	12-1984	Knoke et al.	428/90
*	E	US-4,780,359 A	10-1988	Trask et al.	442/224
*	F	US-4,957,794 A	09-1990	Bair, Thomas I.	428/74
*	G	US-4,980,233 A	12-1990	McCullough et al.	428/411.1
*	H	US-5,035,298 A	07-1991	Noxon, Arthur M.	181/295
*	I	US-5,068,001 A	11-1991	Hausling, Reinhold	156/222
*	J	US-5,279,878 A	01-1994	Fottinger et al.	428/102
*	K	US-5,317,113 A	05-1994	Duda, John	181/285
*	L	US-5,459,291 A	10-1995	Haines et al.	181/286
*	M	US-5,665,447 A	09-1997	Greaves et al.	428/68

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/567,684	Applicant(s)/Patent Under Reexamination TAKAYASU ET AL.	
	Examiner Forrest M. Phillips	Art Unit 2837	Page 2 of 4

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,755,900 A	05-1998	Weir et al.	156/62.2
*	B	US-5,766,745 A	06-1998	Smith et al.	428/218
*	C	US-5,824,973 A	10-1998	Haines et al.	181/286
*	D	US-5,945,643 A	08-1999	Casser, Donald J.	181/290
*	E	US-6,034,009 A	03-2000	Sato, Yoshimi	442/388
*	F	US-6,102,465 A	08-2000	Nemoto et al.	296/39.3
*	G	US-6,123,172 A	09-2000	Byrd et al.	181/290
*	H	US-6,123,171 A	09-2000	McNett et al.	181/290
*	I	US-6,296,076 B1	10-2001	Hiers et al.	181/290
*	J	US-2001/0036788 A1	11-2001	Sandoe et al.	442/389
*	K	US-6,345,688 B1	02-2002	Veen et al.	181/290
*	L	US-6,489,256 B1	12-2002	Kent et al.	442/302
*	M	US-2002/0197442 A1	12-2002	Wyner et al.	428/85

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/567,684	Applicant(s)/Patent Under Reexamination TAKAYASU ET AL.	
	Examiner Forrest M. Phillips	Art Unit 2837	Page 3 of 4

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0220036 A1	11-2003	Lee et al.	442/153
*	B	US-2004/0048036 A1	03-2004	Nakasuji et al.	428/095
*	C	US-6,756,332 B2	06-2004	Sandoe et al.	442/344
*	D	US-2004/0189042 A1	09-2004	Jarrard et al.	296/136.01
*	E	US-6,946,196 B2	09-2005	Foss, Stephen W.	428/373
*	F	US-2005/0249931 A1	11-2005	Utsumi, Akira	428/218
*	G	US-2006/0035555 A1	02-2006	Narayanan et al.	442/387
*	H	US-2006/0141884 A1	06-2006	Haque, Enamul	442/361
*	I	US-2006/0137799 A1	06-2006	Haque et al.	156/062.2
*	J	US-RE39,260 E	09-2006	Byrd et al.	181/290
*	K	US-2006/0225952 A1	10-2006	Takayasu et al.	181/294
*	L	US-2006/0289231 A1	12-2006	Priebe et al.	181/290
*	M	US-2006/0289230 A1	12-2006	Connelly et al.	181/290

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/567,684	Applicant(s)/Patent Under Reexamination TAKAYASU ET AL.	
	Examiner Forrest M. Phillips	Art Unit 2837	Page 4 of 4

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2007/0007062 A1	01-2007	Ogawa et al.	180/069.23
*	B	US-7,178,630 B1	02-2007	Perdue, Jay	181/290
*	C	US-2007/0144829 A1	06-2007	ISHIKAWA et al.	181/286
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.